

Issue Date: Ref. Report No. May 3, 2012 ISL-12HE118CE

Product Name	:	Network Attached Storage
Models	:	TS-1679U-RP; TS-EC1679U-RP; TS-1679U-RP+; TS-EC1679U-RP+;
		TS-1679U II-RP; TS-EC1679U II-RP; NAS-1679UG-RP;
		NAS-EC1679UG-RP; NAS-1679UG-RP+; NAS-EC1679UG-RP+;
		NAS-1679UG II-RP; NAS-EC1679UG II-RP
Brand	:	QNAP
Responsible Party	:	QNAP Systems, Inc.
Address	:	2F, No.22, Zhongxing Rd., Xizhi Dist., New Taipei City 221, Taiwan

We, International Standards Laboratory, hereby certify that:

The device bearing the trade name and model specified above has been shown to comply with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in European Council Directive- EMC Directive 2004/108/EC. The device was passed the test performed according to :

Standards:

CE

EN 55022: 2010 / CISPR 22: 2008 (MOD) EN 61000-3-2: 2006+A1:2009 +A2:2009 / IEC 61000-3-2: 2005+A1:2008 +A2:2009 EN 61000-3-3: 2008 and IEC 61000-3-3: 2008 EN 55024: 2010 / CISPR 24: 2010 EN 61000-4-2: 2009 and IEC 61000-4-2: 2008 EN 61000-4-3: 2006+A1: 2008 +A2: 2010 and IEC 61000-4-3: 2006+A1: 2007+A2: 2010 EN 61000-4-4: 2004 +A1:2010 and IEC 61000-4-4: 2004 +A1:2010 EN 61000-4-5: 2006 and IEC 61000-4-5: 2005 EN 61000-4-6: 2009 and IEC 61000-4-8: 2009 EN 61000-4-8: 2010 and IEC 61000-4-8: 2009 EN 61000-4-11: 2004 and IEC 61000-4-11: 2004

I attest to the accuracy of data and all measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

International Standards Laboratory

Jim Chu

Jim Chu / Director

☑ Hsi-Chih LAB:
 No. 65, Gu Dai Keng St., Hsichih District,
 New Taipei City 22117, Taiwan
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Nemko

CE MARK TECHNICAL FILE

AS/NZS EMC CONSTRUCTION FILE

of

Product Name

Network Attached Storage

Models

TS-1679U-RP; TS-EC1679U-RP; TS-1679U-RP+; TS-EC1679U-RP+; TS-1679U II-RP; TS-EC1679U II-RP; NAS-1679UG-RP; NAS-EC1679UG-RP; NAS-1679UG-RP+; NAS-EC1679UG-RP+; NAS-1679UG II-RP; NAS-EC1679UG II-RP

Brand

QNAP

Contains:

- 1. Declaration of Conformity
- 2. EN55022/CISPR 22, AS/NZS CISPR 22 EMI test report
- 3. EN55024/CISPR 24, EN61000-3-2 / IEC 61000-3-2, and EN61000-3-3 / IEC 61000-3-3 test report
- 4. Certificate of EN60950-1
- 5. Block Diagram and Schematics
- 6. Users' manual

Declaration of Conformity

Name of Responsible Party:	QNAP Systems, Inc.
Address of Responsible Party:	2F, No.22, Zhongxing Rd., Xizhi Dist., New Taipei City 221, Taiwan
Declares that product:	Network Attached Storage
Models:	TS-1679U-RP; TS-EC1679U-RP; TS-1679U-RP+; TS-EC1679U-RP+; TS-1679U II-RP; TS-EC1679U II-RP; NAS-1679UG-RP; NAS-EC1679UG-RP; NAS-1679UG-RP+; NAS-EC1679UG-RP+; NAS-1679UG II-RP; NAS-EC1679UG II-RP
Brand:	QNAP
Assembled by:	Same as above
Address:	Same as above

Conforms to the EMC Directive 2004/108/EC as attested by conformity with the following harmonized standards:

EN 55022:2010 / CISPR 22:2008 (MOD) / AS/NZS CISPR 22: 2009: Limits and methods of measurement of Radio Interference characteristics of Information Technology Equipment. EN 55024:2010 / CISPR 24:2010: Information technology equipment-Immunity characteristics - Limits and methods of measurement.

Standard	Description	Results	Criteria
EN 61000-4-2:2009 IEC 61000-4-2:2008	Electrostatic Discharge	Pass	В
EN 61000-4-3:2006+A1:2008 +A2:2010 IEC 61000-4-3:2006+A1:2007+A2:2010	Radio-Frequency, Electromagnetic Field	Pass	А
EN 61000-4-4: 2004 +A1:2010 IEC 61000-4-4: 2004 +A1:2010	Electrical Fast Transient/Burst	Pass	В
EN 61000-4-5: 2006 IEC 61000-4-5: 2005	Surge	Pass	В
EN 61000-4-6:2009 IEC 61000-4-6:2008	Conductive Disturbance	Pass	А
EN 61000-4-8:2010 IEC 61000-4-8:2009	Power Frequency Magnetic Field	Pass	А
EN 61000-4-11: 2004 IEC 61000-4-11: 2004	Voltage Dips / Short Interruption and Voltage Variation		
	>95% in 0.5 period	Pass	В
	30% in 25 period	Pass	С
	>95% in 250 period	Pass	С

<to be continued>

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Standard	Description	Results
EN 61000-3-2: 2006 +A1:2009 +A2:2009 IEC 61000-3-2: 2005 +A1:2008 +A2:2009	Limits for harmonics current emissions	Pass
EN 61000-3-3: 2008 IEC 61000-3-3: 2008	Limits for voltage fluctuations and flicker in low-voltage supply systems.	Pass

Conforms to the Low Voltage Directive 2006/95/EC, 93/68/EEC as attested by conformity with the following harmonized standard:

EN60950-1:2006+A11:2009: Safety of Information Technology Equipment Including electrical business equipment

We, QNAP Systems, Inc., hereby declare that the equipment bearing the trade name and model number specified above was tested conforming to the applicable Rules under the most accurate measurement standards possible, and that all the necessary steps have been taken and are in force to assure that production units of the same equipment will continue to comply with the requirements.

QNAP Systems, Inc.	
Date: May 3, 2012	

Declaration of Conformity

Name of Responsible Party:	QNAP Systems, Inc.
Address of Responsible Party:	2F, No.22, Zhongxing Rd., Xizhi Dist., New Taipei City 221, Taiwan
Declares that product:	Network Attached Storage
Models:	TS-1679U-RP; TS-EC1679U-RP; TS-1679U-RP+; TS-EC1679U-RP+; TS-1679U II-RP; TS-EC1679U II-RP; NAS-1679UG-RP; NAS-EC1679UG-RP; NAS-1679UG-RP+; NAS-EC1679UG-RP+; NAS-1679UG II-RP; NAS-EC1679UG II-RP
Brand:	QNAP
Assembled by:	Same as above
Address:	Same as above

Conforms to the C-Tick Mark requirement as attested by conformity with the following standards:

EN 55022:2010 / CISPR 22:2008 (MOD) / AS/NZS CISPR 22: 2009: Limits and methods of measurement of Radio Interference characteristics of Information Technology Equipment. EN 55024:2010 / CISPR 24:2010: Information technology equipment-Immunity characteristics - Limits and methods of measurement.

Standard	Description	Results	Criteria
EN 61000-4-2:2009 IEC 61000-4-2:2008	Electrostatic Discharge	Pass	В
EN 61000-4-3:2006+A1:2008 +A2:2010 IEC 61000-4-3:2006+A1:2007+A2:2010	Radio-Frequency, Electromagnetic Field	Pass	А
EN 61000-4-4: 2004 +A1:2010 IEC 61000-4-4: 2004 +A1:2010	Electrical Fast Transient/Burst	Pass	В
EN 61000-4-5: 2006 IEC 61000-4-5: 2005	Surge	Pass	В
EN 61000-4-6:2009 IEC 61000-4-6:2008	Conductive Disturbance	Pass	А
EN 61000-4-8:2010 IEC 61000-4-8:2009	Power Frequency Magnetic Field	Pass	А
EN 61000-4-11: 2004 IEC 61000-4-11: 2004	Voltage Dips / Short Interruption and Voltage Variation		
	>95% in 0.5 period	Pass	В
	30% in 25 period	Pass	С
	>95% in 250 period	Pass	С

<to be continued>

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Standard	Description	Results
EN 61000-3-2: 2006 +A1:2009 +A2:2009 IEC 61000-3-2: 2005 +A1:2008 +A2:2009	Limits for harmonics current emissions	Pass
EN 61000-3-3: 2008 IEC 61000-3-3: 2008	Limits for voltage fluctuations and flicker in low-voltage supply systems.	Pass

We, QNAP Systems, Inc., hereby declare that the equipment bearing the trade name and model number specified above was tested conforming to the applicable Rules under the most accurate measurement standards possible, and that all the necessary steps have been taken and are in force to assure that production units of the same equipment will continue to comply with the requirements.

QNAP Systems, Inc.

Date: May 3, 2012



CE TEST REPORT

of

EN55022 / CISPR 22 / AS/NZS CISPR 22 Class A EN55024 / CISPR 24 / IMMUNITY EN61000-3-2 / EN61000-3-3

Product : Network Attached Storage

Models: TS-1679U-RP; TS-EC1679U-RP; TS-1679U-RP+; TS-EC1679U-RP+; TS-1679U II-RP; TS-EC1679U II-RP; NAS-1679UG-RP; NAS-EC1679UG-RP; NAS-1679UG-RP+; NAS-EC1679UG-RP+; NAS-1679UG II-RP; NAS-EC1679UG II-RP

Brand: **QNAP**

Applicant: QNAP Systems, Inc.

Address: 2F, No.22, Zhongxing Rd., Xizhi Dist., New Taipei City 221, Taiwan

Test Performed by: International Standards Laboratory <Hsi-Chih LAB> *Site Registration No. BSMI:SL2-IN-E-0037; SL2-R1/R2-E-0037; TAF: 1178; IC: IC4067A-1; VCCI: R-341,C-354, T-1749, G-443; NEMKO: ELA 113A *Address: No. 65, Gu Dai Keng St. Hsichih District, New Taipei City 22117, Taiwan *Tel: 886-2-2646-2550; Fax: 886-2-2646-4641

Report No.: ISL-12HE118CE Issue Date : May 3, 2012

This report totally contains 59 pages including this cover page and contents page.

Test results given in this report apply only to the specific sample(s) tested and are traceable to national or international standard through calibration of the equipment and evaluating measurement uncertainty herein.

This test report shall not be reproduced except in full, without the written approval of International Standards Laboratory.



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Appendix D: Photographs of EUT Please refer to the File of ISL-12HE118P......56

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1. General

1.1 Certification of Accuracy of Test Data

Standards:	Please refer to 1.2
Equipment Tested:	Network Attached Storage
Models:	TS-1679U-RP; TS-EC1679U-RP; TS-1679U-RP+;
	TS-EC1679U-RP+; TS-1679U II-RP; TS-EC1679U II-RP; NAS-1679UG-RP; NAS-EC1679UG-RP; NAS-1679UG-RP+; NAS-EC1679UG-RP+; NAS-1679UG II-RP; NAS-EC1679UG II-RP
Brand:	QNAP
Applicant:	QNAP Systems, Inc.
Sample received Date:	April 16, 2012
Final test Date:	EMI: refer to the date of test data
	EMS: May 10, 2012
Test Site:	International Standards Laboratory
	OATS 01; Chamber 01; Conduction 01; Immunity01
Test Distance:	10M; 3M (above1GHz) (EMI test)
Temperature:	refer to each site test data
Humidity:	refer to each site test data
Input power:	Conduction input power: AC 230 V / 50 Hz
	Radiation input power: AC 230 V / 50 Hz
Y	Immunity input power: AC 230 V / 50 Hz
Test Result:	PASS
Report Engineer:	Winnie Huang
Test Engineer:	Leuis Yu

Louis Yu

Approved By:

Eddy Flsing Eddy Hsiung



1.2 Test Standards

The tests which this report describes were conducted by an independent electromagnetic compatibility consultant, International Standards Laboratory in accordance with the following

EN 55022:2010 / CISPR 22:2008 (MOD) / AS/NZS CISPR 22: 2009: Class A: Limits and methods of measurement of Radio Interference characteristics of Information Technology Equipment.

EN 55024:2010 / CISPR 24:2010: Information technology equipment-Immunity characteristics - Limits and methods of measurement.

Standard	Description	Results	Criteria
EN 61000-4-2:2009 IEC 61000-4-2:2008	Electrostatic Discharge	Pass	В
EN 61000-4-3:2006+A1:2008 +A2:2010 IEC 61000-4-3:2006+A1:2007+A2:2010	Radio-Frequency, Electromagnetic Field	Pass	А
EN 61000-4-4: 2004 +A1:2010 IEC 61000-4-4: 2004 +A1:2010	Electrical Fast Transient/Burst	Pass	В
EN 61000-4-5: 2006 IEC 61000-4-5: 2005	Surge	Pass	В
EN 61000-4-6:2009 IEC 61000-4-6:2008	Conductive Disturbance	Pass	А
EN 61000-4-8:2010 IEC 61000-4-8:2009	Power Frequency Magnetic Field	Pass	А
EN 61000-4-11: 2004 IEC 61000-4-11: 2004	Voltage Dips / Short Interruption and Voltage Variation		
	>95% in 0.5 period	Pass	В
	30% in 25 period	Pass	С
X	>95% in 250 period	Pass	С

Standard	Description	Results
EN 61000-3-2: 2006 +A1:2009 +A2:2009 IEC 61000-3-2: 2005 +A1:2008 +A2:2009	Limits for harmonics current emissions	Pass
EN 61000-3-3: 2008 IEC 61000-3-3: 2008	Limits for voltage fluctuations and flicker in low-voltage supply systems.	Pass



1.3 Description of EUT

EUT			
Description:	Network Attached Storage		
Condition:	Pre-Production		
Models:	TS-1679U-RP; TS-EC1679U-RP; TS-1679U-RP+;		
	TS-EC1679U-RP+; TS-1679U II-RP; TS-EC1679U II-RP;		
	NAS-1679UG-RP; NAS-EC1679UG-RP; NAS-1679UG-RP+;		
	NAS-EC1679UG-RP+; NAS-1679UG II-RP; NAS-EC1679UG		
	II-RP		
Serial Number:	N/A		
Power Supply Type:	two DELTA (Model: DPS-600SB D)		
	AC Input: 100-240V~/ 10A		
	DC Output:		
	+12V 49A		
	+5VSB 3A		
	Total output wattage: 600W MAX.		
CPU:	Intel® Xeon® Processor E3-1225 3.1GHz		
	Intel® Core TM i3-2120 Processor 3.3GHz		
Motherboard:	(Model: TS-1679U V13)		
SATA board:	(Model: TS-1679U 6G BP V11)		
DIMM Memory:	two ADATA (Model: SU3E1333C4G9-B)		
	4GB DDR3-1333MHz		
USB Flash:	one		
Power Switch Button:	one		
USB 2.0 Port:	four (4-pins)		
USB 3.0 Port:	two (9-pins)		
E-Serial ATA Port:	two (7-pins)		
D-Sub Port:	one 15-pins		
HDMI Port:	one 19-pins		
SATA Hard Disk:	Western Digital (Model: WD5000AADS-00S9B0)		
	500GB * 16		
RJ45 Connector:	four (8-pins) (10/100/1000Mbps)		
AC Power Port:	two		
Highest frequency of the interna	al sources of the EUT is 3.1GHz		



All types of EUT Connect have been tested. W	Ve present the worst case test data
(Configurations 1) in the report.	

Configuration	CPU	Output Display Type
S		
1	Intel® Xeon® Processor	HDMI
	E3-1225 3.1GHz	
2	Intel® Xeon® Processor	D-SUB
	E3-1225 3.1GHz	
3	Intel [®] Core [™] i3-2120 Processor	HDMI
	3.3GHz	
4	Intel [®] Core [™] i3-2120 Processor	D-SUB
	3.3GHz	

EMI Noise Source

Motherboard Crystal:	25MHz(Y1),25MHz (Y2),25MHz (Y3),25MHz (Y4),
	25MHz (X1),32.768KHz (X2),25MHz (X3)
SATA Board Crystal:	25MHz (Y1),25MHz (Y2),25MHz (Y3),25MHz (Y4),
	25MHz (Y5),25MHz (Y6),25MHz (Y7),25MHz (U20)
USB Flash Crystal:	12MHz (Y1)

EMI Solution:

1. Added one Gasket on the Motherboard contact housing. (Reference EUT photo 29)

	piloto 29)	
Model differences:		
Model	Package	Selling markets
TS-1679U-RP	Carton Box	Commercial storage related products supply chain management
TS-EC1679U-RP	Carton Box	Commercial storage related products supply chain management
TS-1679U-RP+	Carton Box	Industrial storage related products supply chain management
TS-EC1679U-RP+	Carton Box	Industrial storage related products supply chain management
TS-1679U II-RP	Carton Box	Professional / Industrial storage related products supply chain management
TS-EC1679U II-RP	Carton Box	Professional / Industrial storage related products supply chain management
NAS-1679UG-RP	Carton Box (No Logo)	Commercial Storage equipment Tender and Cooperation plan
NAS-EC1679UG-RP	Carton Box (No Logo)	Commercial Storage equipment Tender and Cooperation plan
NAS-1679UG-RP+	Carton Box (No Logo)	Industrial Storage equipment Tender and Cooperation plan
NAS-EC1679UG-RP+	Carton Box (No Logo)	Industrial Storage equipment Tender and Cooperation plan
NAS-1679UG II-RP	Carton Box (No Logo)	Professional / Industrial Storage equipment Tender and Cooperation plan

I

Carton Box (No Logo)

NAS-EC1679UG II-RP

Professional / Industrial Storage equipment Tender and

Cooperation plan



1.4 Description of Support Equipment

Unit	Model Serial No.	Brand	Power Cord	FCC ID
Notebook Personal Computer	Latitude D400 S/N: N/A	DELL	Non-shielded, Detachable	FCC DOC
Rack mountable Switch	DGS-1008D	D-Link	D-Link (Model:AF-1205-B)	FCC DOC
24" LCD Monitor	U2410	DELL	Non-Shielded, Detachable	FCC DOC
External HDD Enclosure*4	RD1000 S/N: N/A	DELL	Non-Shielded, Detachable	FCC DOC
External HDD Enclosure*2	WDBACY5000ABK-PESN S/N: WXH1E31FSV80	WD	Non-Shielded, Detachable	FCC DOC
E-SATA External Hard Disk*2	NST-200SU-BK S/N: N/A	NexStar	Non-shielded, Detachable	FCC DOC



International Standards Laboratory



1.5 Software for Controlling Support Unit

Test programs exercising various part of EUT were used. The programs were executed as follows:

- A. Send EUT Information to the video port device (LCD Monitor).
- B. Read and write to the disk drives.
- C. Send package to the Router LAN port (Router).
- D. Receive and transmit package of EUT to the Rack mountable Switch HUB through LAN port.
- E. Used Tfgen.exe to send signal to EUT RJ45 port through PC RJ45 Port.F. Read and write data in the USB2.0 Hard Disk through EUT USB2.0 port.
- G. Read and write data in the USB3.0 Hard Disk through EUT USB3.0 port.
- H. Read and write data in the E-SATA Hard Disk through EUT E-SATA port.
- I. Search External HDD from PC RJ45 to EUT RJ45 with Finder.exe.
- J. Repeat the above steps.

	Filename	Issued Date
External Hard Disk	InterEMC.exe	9/04/2000
Drive Station USB3.0 Hard Drive	InterEMC.exe	9/04/2000
E-SATA External Hard Disk	InterEMC.exe	9/04/2000
LAN	ping.exe	05/05/1999
LAN	Tfgen.exe	06/23/1999
EUT	Finder.exe	11/15/2008
EUT Hard Disk	InterEMC.exe	9/04/2000



1.6 I/O Cable Condition of EUT and Support Units

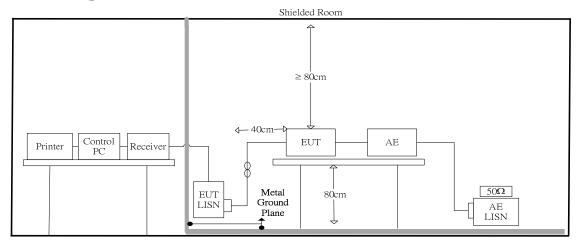
Description	Path	Cable Length	Cable Type	Connector Type
AC Power Cord	110V (~240V) to EUT SPS	1.8M	Non-shielded, Detachable	Plastic Head
USB Data Cable*4	External HDD Enclosure USB 2.0Port to EUT USB 2.0Port	2M	Shielded, Detachable (With Core)	Metal Head
USB3.0 Data Cable*2	External HDD Enclosure USB 3.0 Port to EUT USB 3.0Port	1.0M	Shielded, Detachable	Metal Head
E-SATA Data Cable*2	E-SATA Hard Disk E-SATA Port to EUT E-SATA Port	1.0M	Non-Shielded, Detachable	Plastic Head
LAN Data Cable	Notebook LAN port to Switch HUB LAN Port	1.0M	Non-shielded, Detachable	RJ-45, with Plastic Head
LAN Data Cable*2	EUT LAN Port to Switch HUB LAN Port	10M	Non-shielded, Detachable	RJ-45, with Plastic Head
Display Data Cable	EUT HDMI Port to LCD Monitor HDMI Port	1. 8M	Shielded, Detachable	Metal Head
Display Data Cable	EUT D-sub Port to LCD Monitor D-sub Port	1.98M	Shielded, Detachable (With Core)	Metal Head



2. Power Main Port Conducted Emissions

2.1 Test Setup and Procedure

2.1.1 Test Setup



2.1.2 Test Procedure

The measurements are performed in a $3.5m \ge 3.4m \ge 2.5m$ shielded room, which referred as Conduction 01 test site, or a $3m \ge 3m \ge 2.3m$ test site, which referred as Conduction 02 test site. The EUT was placed on non-conduction 1.0m $\ge 1.5m$ table, which is 0.8 meters above an earth-grounded.

Power to the EUT was provided through the LISN which has the Impedance (500hm/50uH) vs. Frequency Characteristic in accordance with the standard. Power to the LISNs were filtered to eliminate ambient signal interference and these filters were bonded to the ground plane. Peripheral equipment required to provide a functional system (support equipment) for EUT testing was powered from the second LISN through a ganged, metal power outlet box which is bonded to the ground plane at the LISN.

The interconnecting cables were arranged and moved to get the maximum measurement. Both the line of power cord, hot and neutral, were measured.

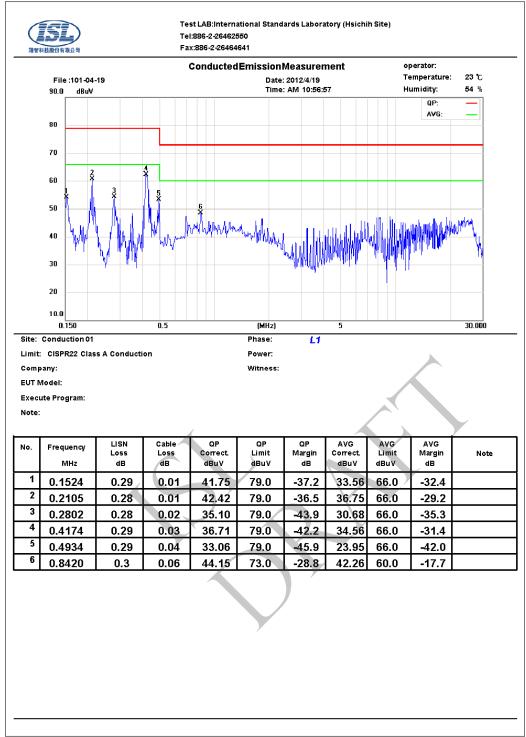
The highest emissions were analyzed in details by operating the spectrum analyzer in fixed tuned mode to determine the nature of the emissions and to provide information which could be useful in reducing their amplitude.

2.1.3 EMI Receiver/Spectrum Analyzer Configuration (for the frequencies tested)

Frequency Range:	150KHz30MHz
Detector Function:	Quasi-Peak / Average Mode
Resolution Bandwidth:	9KHz



2.2 Conduction Test Data: Configuration 1 Table 2.2.1 Power Line Conducted Emissions (Hot)



Note:

Margin = Corrected Amplitude - Limit

Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



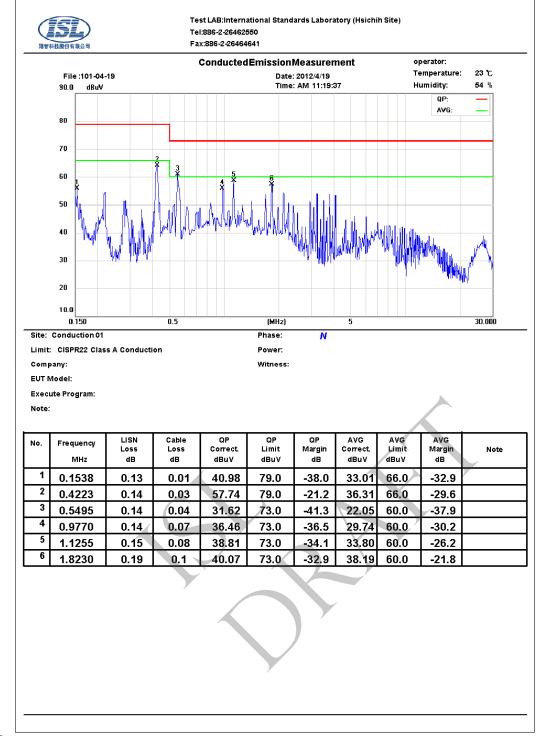


Table 2.2.2 Power Line Conducted Emissions (Neutral)

Note:

Margin = Corrected Amplitude - Limit

Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result. If peak data can pass, it will be shown in "QP/AVG Correct" column, if not, QP/AVG data will instead.

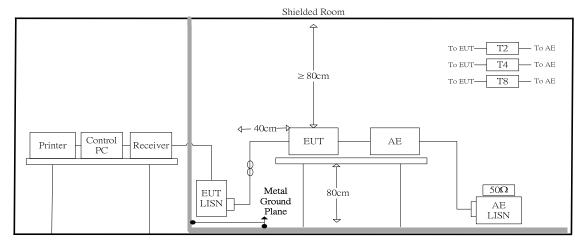




3. Telecommunication Port Conducted Emissions

3.1 Test Setup and Procedure

3.1.1 Test Setup



3.1.2 Test Procedure

The measurements are performed in a $3.5m \times 3.4m \times 2.5m$ shielded room, which referred as Conduction 01 test site, or a $3m \times 3m \times 2.3m$ test site, which referred as Conduction 02 test site. The EUT was placed on non-conduction 1.0m x 1.5m table, which is 0.8 meters above an earth-grounded.

The EUT, any support equipment, and any interconnecting cables were arranged and moved to get the maximum measurement.

Power to the EUT was provided through the LISN which has the Impedance (50 Ohm/50uH) vs. Frequency Characteristic in accordance with the standard. Power to the LISN was filtered to eliminate ambient signal interference and this filter was bonded to ground. Peripheral equipment to provide a functional system (support equipment) for EUT testing was powered through a ganged, metal power outlet box bonded to the ground. AC input power for the auxiliary power outlets was obtained from the same filtered source that provides input power to the LISN.

The highest emissions were analyzed in details by operating the spectrum analyzer in fixed tuned mode to determine the nature of the emissions and to provide information could be useful in reducing their amplitude.

3.1.3 EMI Receiver/Spectrum Analyzer Configuration (for the frequencies tested)

Frequency Range:	150KHz30MHz
Detector Function:	Quasi-Peak / Average Mode
Resolution Bandwidth:	9KHz



3.2 Test Data: LAN--10M: Configuration 1

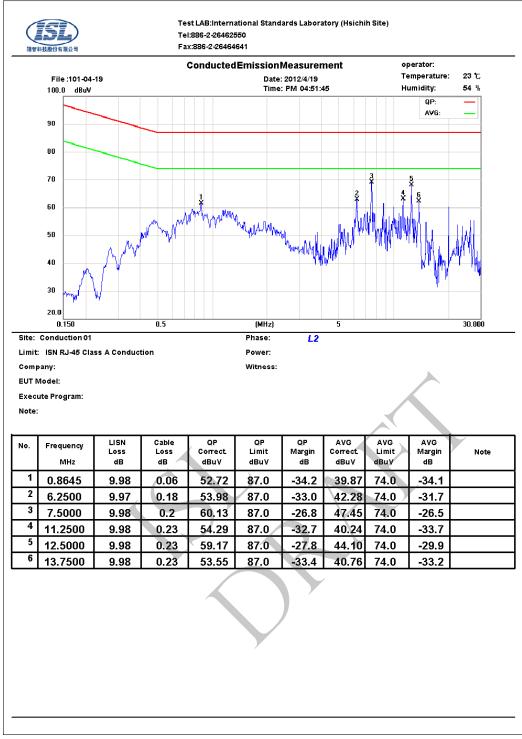


Table 3.2.1 Telecommunication Port Conducted Emission

Note :

Margin = Corrected Amplitude - Limit

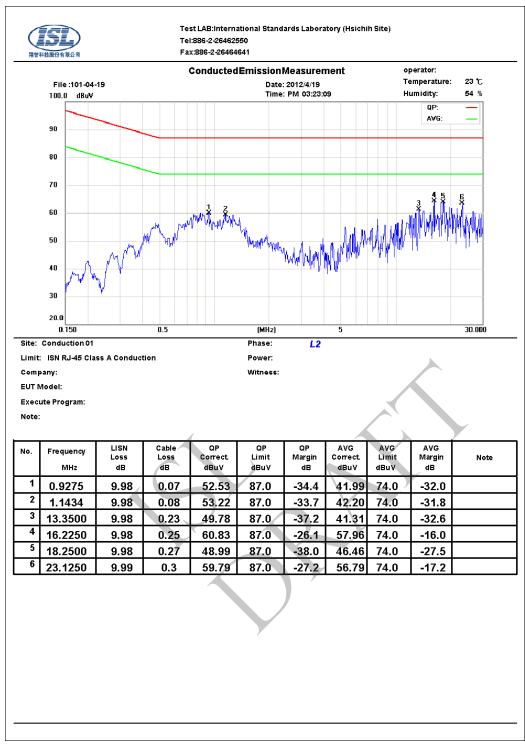
Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



3.3 Test Data: LAN--100M: Configuration 1 Table 3.3.1 Telecommunication Port Conducted Emission



Note :

Margin = Corrected Amplitude - Limit

Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



Table 3.4.1 Telecommunication Port Conducted Emission Test LAB:International Standards Laboratory (Hsichih Site) Tel:886-2-26462550 Fax:886-2-26464641 ConductedEmissionMeasurement operator: Date: 2012/4/19 Temperature: 23 ℃ File :101-04-19 Time: PM 01:52:29 Humidity: 54 % 100.0 dBuV QP: AVG: 90 80 70 WWWWWWWWWWW 60 50 WAR HANNAND 40 30 20.0 30.000 0.150 0.5 (MHz) 5 Site: Conduction 01 Phase: L2 Limit: ISN RJ-45 Giga Class A Conduction Power: Company: Witness: EUT Model: Execute Program: Note: LISN Cable QP QP QP AVG AVG Limit AVG No. Frequency Loss Loss orrect Limit Margin Correct Margin Note MHz dB dB dBuV dBuV dB dBuV dBuV dB 1 0.7160 10.03 40.73 74.0 0.05 50.87 87.0 -36.1 -33.2 2 74.0 0.7880 10.03 0.06 52.48 87.0 -34.5 41.55 -32.4 3 0.06 0.8375 10.02 50.82 87.0 -36.1 40.45 74.0 -33.5 4 1.0715 10.01 0.07 49.25 87.0 -37.7 39.56 74.0 -34.4 5 1.1390 10.01 0.08 50.35 87.0 -36.6 40.55 74.0 -33.4 6 1.2965 10.02 0.08 51.50 87.0 -35.5 41.68 74.0 -32.3

3.4 Test Data: LAN--GIGA: Configuration 1 Table 3.4.1 Telecommunication Port Conducted Emission

Note :

Margin = Corrected Amplitude - Limit

Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



3.5 Test Data: LAN--10M: Configuration 2

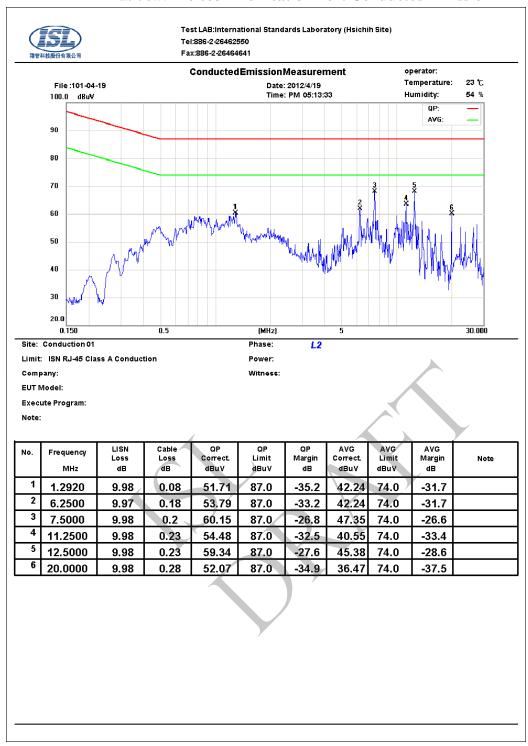


Table 3.5.1 Telecommunication Port Conducted Emission

Note :

Margin = Corrected Amplitude - Limit

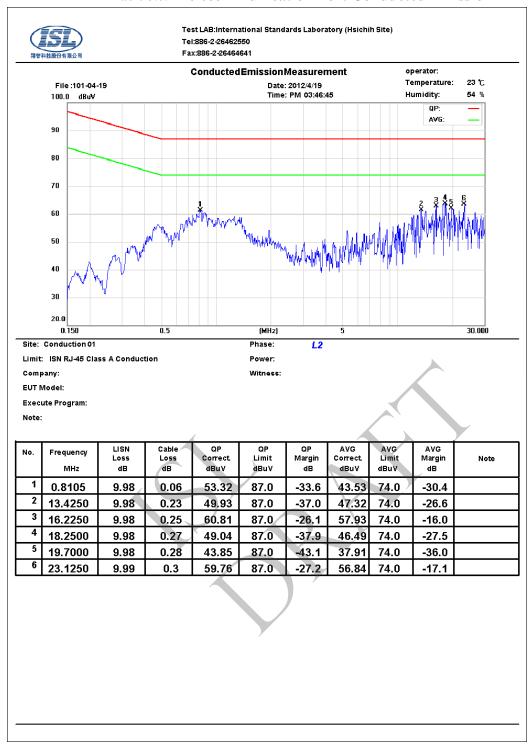
Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



3.6 Test Data: LAN--100M: Configuration 2 Table 3.6.1 Telecommunication Port Conducted Emission



Note :

Margin = Corrected Amplitude - Limit

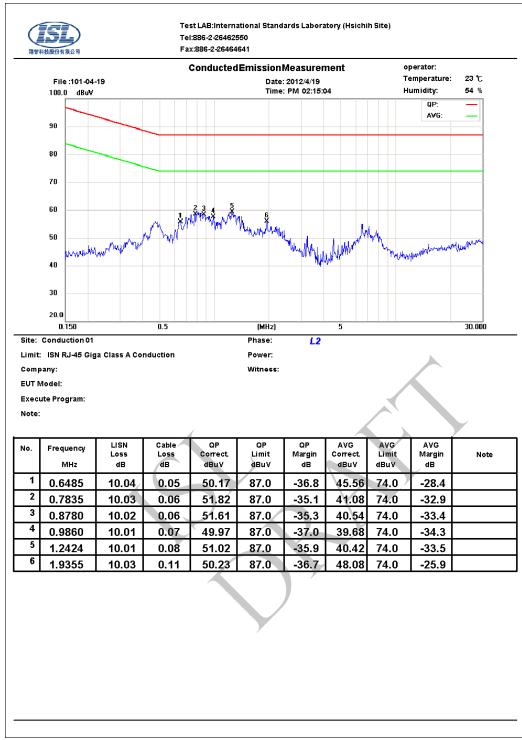
Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



3.7 Test Data: LAN--GIGA: Configuration 2 Table 3.7.1 Telecommunication Port Conducted Emission



Note :

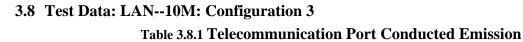
Margin = Corrected Amplitude - Limit

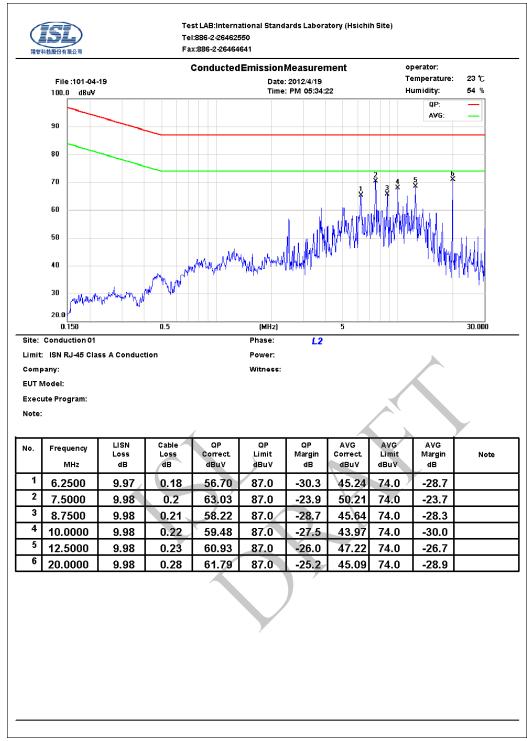
Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.







Note :

Margin = Corrected Amplitude - Limit

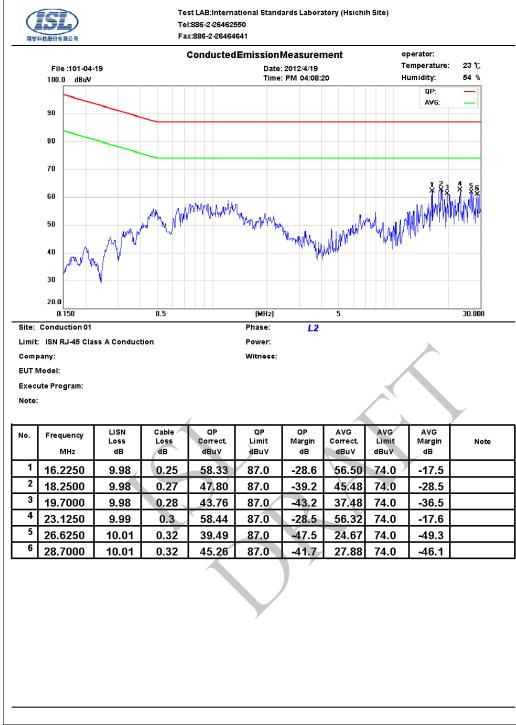
Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



3.9 Test Data: LAN--100M: Configuration 3 Table 3.9.1 Telecommunication Port Conducted Emission



Note :

Margin = Corrected Amplitude - Limit

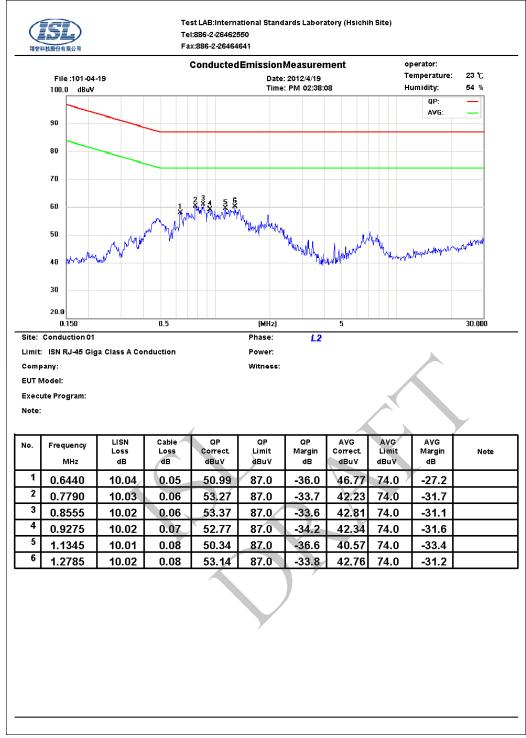
Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



3.10 Test Data: LAN--GIGA: Configuration 3 Table 3.10.1 Telecommunication Port Conducted Emission



Note :

Margin = Corrected Amplitude - Limit

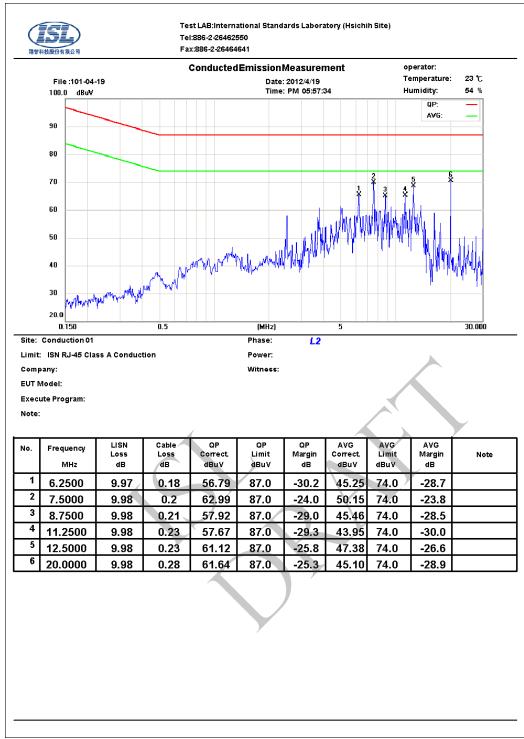
Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



3.11 Test Data: LAN--10M: Configuration 4 Table 3.11.1 Telecommunication Port Conducted Emission



Note :

Margin = Corrected Amplitude - Limit

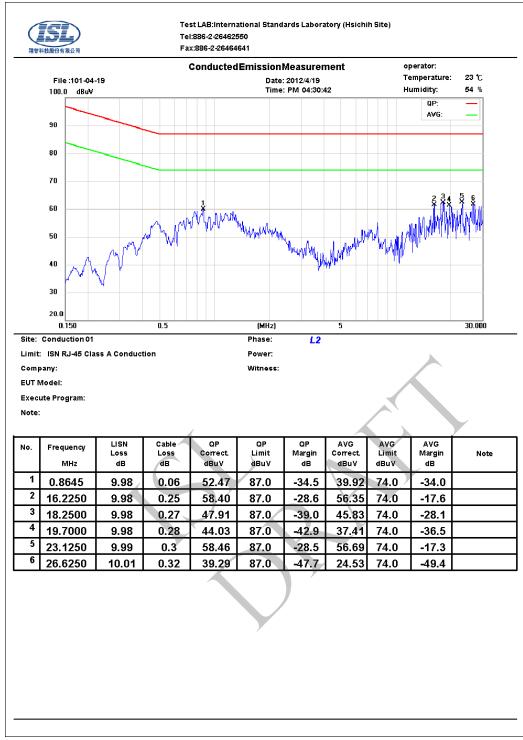
Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



3.12 Test Data: LAN--100M: Configuration 4 Table 3.12.1 Telecommunication Port Conducted Emission



Note :

Margin = Corrected Amplitude - Limit

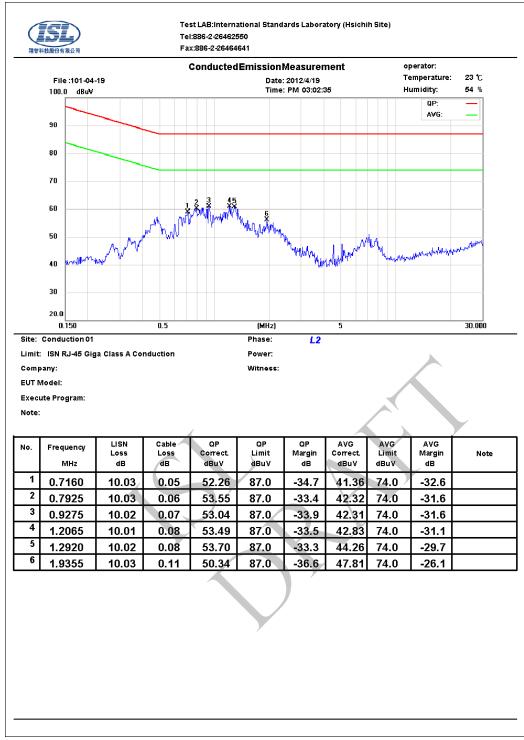
Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



3.13 Test Data: LAN--GIGA: Configuration 4 Table 3.13.1 Telecommunication Port Conducted Emission



Note :

Margin = Corrected Amplitude - Limit

Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

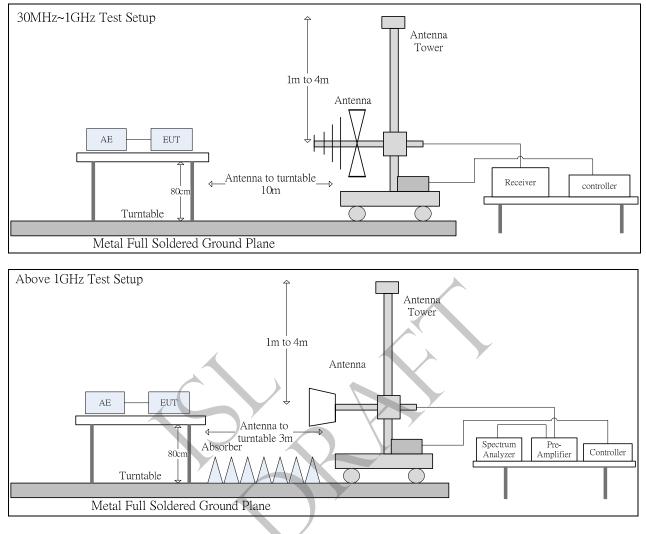
The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.



4. Radiated Disturbance Emissions

4.1 Test Setup and Procedure

4.1.1 Test Setup



4.1.2 Test Procedure

The radiated emissions test will then be repeated on the open site or chamber to measure the amplitudes accurately and without the multiple reflections existing in the shielded room. The EUT and support equipment are set up on the turntable of one of 10 meter open field sites or 10 meter chamber. Desktop EUT are set up on a wooden stand 0.8 meter above the ground or floor-standing arrangement shall be placed on the horizontal ground reference plane. The test volume for a height of up to 30 cm may be obstructed by absorber placed on the ground plane.

For the initial measurements, the receiving antenna is varied from 1-4 meter height and is changed in the vertical plane from vertical to horizontal polarization at each frequency. The highest emissions between 30 MHz to 1000 MHz were analyzed in details by operating the spectrum analyzer and/or EMI receiver in quasi-peak mode to determine the precise amplitude of the emissions. The highest emissions between 1 GHz to 6 GHz were analyzed in details by operating

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the spectrum analyzer in peak and average mode to determine the precise amplitude of the emissions.

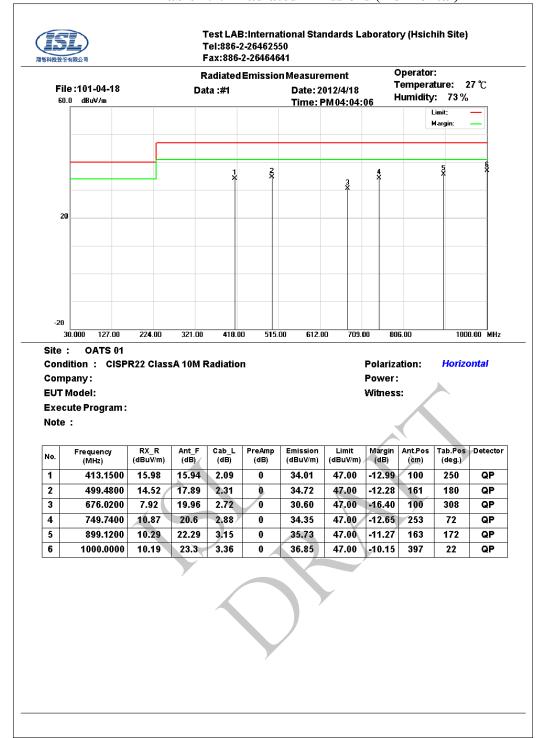
At the highest amplitudes observed, the EUT is rotated in the horizontal plane while changing the antenna polarization in the vertical plane to maximize the reading. The interconnecting cables were arranged and moved to get the maximum measurement. Once the maximum reading is obtained, the antenna elevation and polarization will be varied between specified limits to maximize the readings.

The highest internal source of an EUT is defined as the highest frequency generated or used within the EUT or on which the EUT operates or tunes. If the highest frequency of the internal sources of the EUT is less than 108 MHz, the measurement shall only be made up to 1 GHz. If the highest frequency of the internal sources of the EUT is between 108 MHz and 500 MHz, the measurement shall only be made up to 2 GHz. If the highest frequency of the internal sources of the EUT is between 500 MHz and 1 GHz, the measurement shall only be made up to 5 GHz. If the highest frequency of the internal sources of the EUT is above 1 GHz, the measurement shall be made up to 5 times the highest frequency or 6 GHz, whichever is less.

4.1.3 Spectrum Analyzer Configuration (for the frequencies tested)

Frequency Range:	30MHz1000MHz	
Detector Function:	Quasi-Peak Mode	
Resolution Bandwidth:	120KHz	
Frequency Range:	Above 1 GHz to 6 GHz	
Detector Function:	Peak/Average Mode	
Resolution Bandwidth:	1MHz	





4.2 Radiation Test Data: Configuration 1 Table 4.2.1 Radiated Emissions (Horizontal)

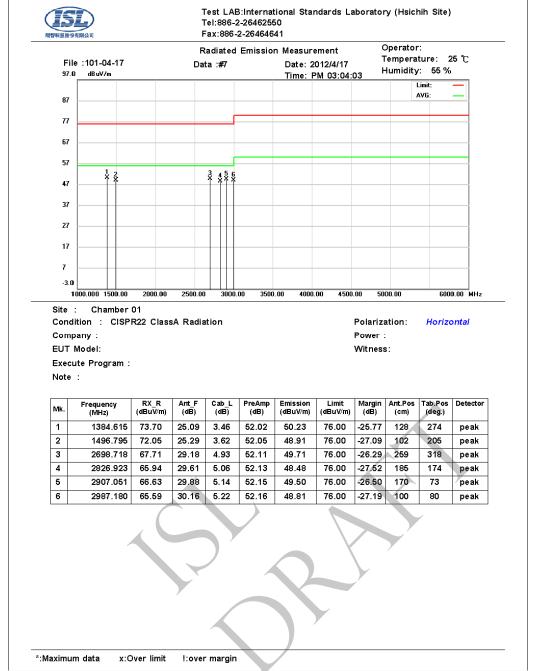
* Note:

Margin = Corrected Amplitude – Limit

Corrected Amplitude = Radiated Amplitude + Antenna Correction Factor + Cable Loss – Pre-Amplifier Gain A margin of -8dB means that the emission is 8dB below the limit BILOG Antenna Distance: 10 meters

Below 1GHz test, if the peak measured value meets the QP limit, it is unnecessary to perform the QP measurement.





* Note:

Margin = Corrected Amplitude - Limit

Corrected Amplitude = Radiated Amplitude + Antenna Correction Factor + Cable Loss – Pre-Amplifier Gain A margin of -8dB means that the emission is 8dB below the limit Horn Antenna Distance: 3 meters

Distance. 5 meters

Above 1GHz test, if the peak measured value meets the average limit, it is unnecessary to perform the average measurement.



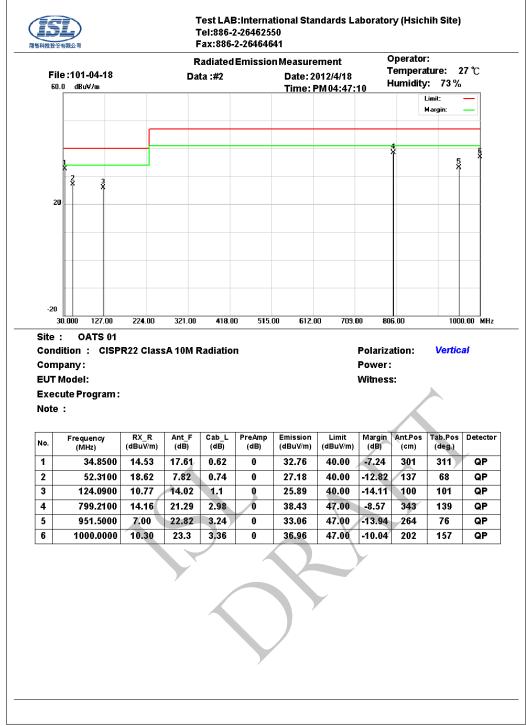


Table 4.2.2 Radiated Emissions (Vertical)

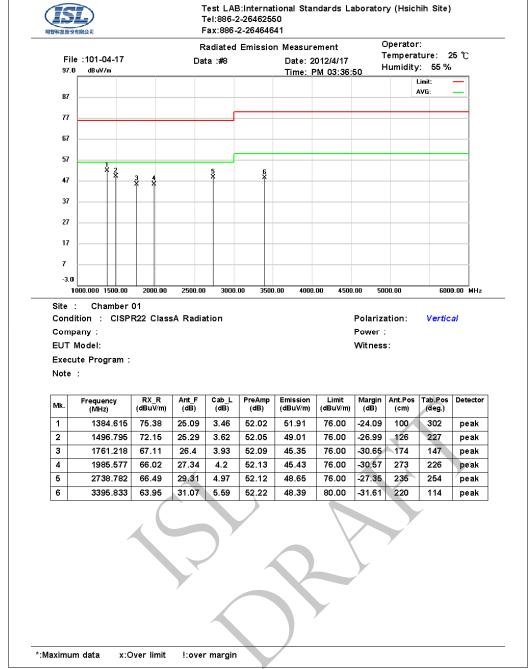
* Note:

Margin = Corrected Amplitude - Limit

Corrected Amplitude = Radiated Amplitude + Antenna Correction Factor + Cable Loss – Pre-Amplifier Gain A margin of -8dB means that the emission is 8dB below the limit BILOG Antenna Distance: 10 meters

Below 1GHz test, if the peak measured value meets the QP limit, it is unnecessary to perform the QP measurement.





* Note:

Margin = Corrected Amplitude - Limit

Corrected Amplitude = Radiated Amplitude + Antenna Correction Factor + Cable Loss – Pre-Amplifier Gain A margin of -8dB means that the emission is 8dB below the limit Horn Antenna Distance: 3 meters

Above 1GHz test, if the peak measured value meets the average limit, it is unnecessary to perform the average measurement.



5. Electrostatic discharge (ESD) immunity

_	
Port:	Enclosure
Basic Standard:	EN 61000-4-2/ IEC EN61000-4-2
	(details referred to Sec 1.2)
Test Level:	Air +/- 2 kV, +/- 4 kV, +/- 8 kV
	Contact +/- 4 kV
Criteria:	В
Test Procedure	refer to ISL QA -T4-E-S7
Temperature:	21 °C
Humidity:	55%

5.1 Test Specification

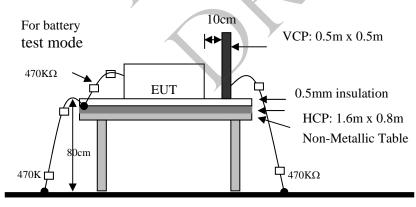
Selected Test Point

- Air: discharges were applied to slots, aperture or insulating surfaces. 10 single air discharges were applied to each selected points.
- Contact: Total 200 discharges minimum were to the selected contact points.
- Indirect Contact Points: 25 discharges were applied to center of one edge of VCP and each EUT side of HCP with 10 cm away from EUT.

Red arrow lines indicate the contact points, and blue arrow lines indicate the air points.

5.2 Test Setup

EUT is 1m from the wall and other metallic structure. When Battery test mode is needed, a cable with one $470K\Omega$ resister at two rare ends is connected from metallic part of EUT and screwed to HCP.

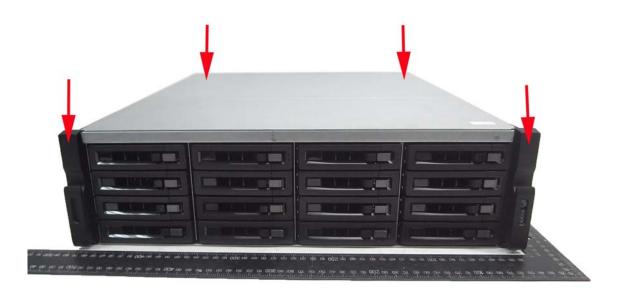


Ground reference Plane

5.3 Test Result



TestPoint:







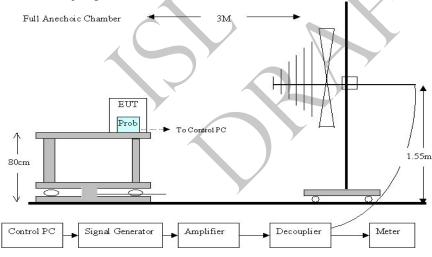
6. Radio-Frequency, Electromagnetic Field immunity

H			
Port:	Enclosure		
Basic Standard:	EN 61000-4-3/ IEC EN61000-4-3		
	(details referred to Sec 1.2)		
Test Level:	3 V/m		
Modulation:	AM 1KHz 80%		
Frequency range:	80 MHz~1 GHz		
Frequency Step:	1% of last step frequency		
Dwell time:	38		
Polarization:	Vertical and Horizontal		
EUT Azimuth Angle	$\boxtimes 0^{\circ} \boxtimes 90^{\circ} \boxtimes 180^{\circ} \boxtimes 270^{\circ}$		
Criteria:	A		
Test Procedure	refer to ISL QA -T4-E-S8		
Temperature:	22°C		
Humidity:	64%		

6.1 Test Specification

6.2 Test Setup

The field sensor is placed at one calibration grid point to check the intensity of the established fields on both polarizations. EUT is adjusted to have each side of EUT face coincident with the calibration plane. A CCD camera and speakers are used to monitor the condition of EUT for the performance judgment.



6.3 Test Result



7. Electrical Fast transients/burst immunity

i i est specification	
Port:	AC mains; Twisted Pair LAN Port
Basic Standard:	EN 61000-4-4/ IEC EN61000-4-4
	(details referred to Sec 1.2)
Test Level:	AC Power Port: +/- 1 kV
	Twisted Pair LAN Port (I/O Cables): +/-
	0.5 kV
Rise Time:	5ns
Hold Time:	50ns
Repetition Frequency:	5KHz
Criteria:	В
Test Procedure	refer to ISL QA -T4-E-S9
Temperature:	21 °C
Humidity:	65%

7.1 Test Specification

Test Procedure

The EUT was setup on a nonconductive table 0.1 m above a reference ground plane.

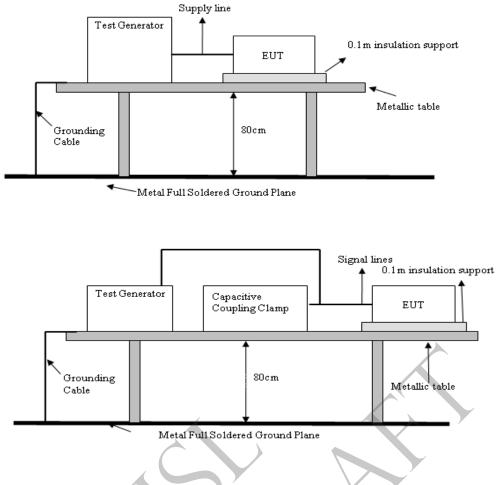
Test Points	Dolomity	Comment	
	Polarity	Result	Comment
Line	+	Ν	60 sec
	-	N	60 sec
Neutral	+	Ν	60 sec
	-	N	60 sec
Ground	+	Ν	60 sec
		Ν	60 sec
Line to	+	N	60 sec
Neutral		N	60 sec
Line to	+	N	60 sec
Ground	-	N	60 sec
Neutral to	+	N	60 sec
Ground	-	Ν	60 sec
Line to Neutral	+	Ν	60 sec
to Ground	- 7	Ν	60 sec
Capacitive coupling	+	Ν	60 sec
clamp	-	Ν	60 sec
3.7			

Note: 'N' means normal, the EUT function is correct during the test.



7.2 Test Setup

EUT is at least 50cm from the conductive structure.



7.3 Test Result

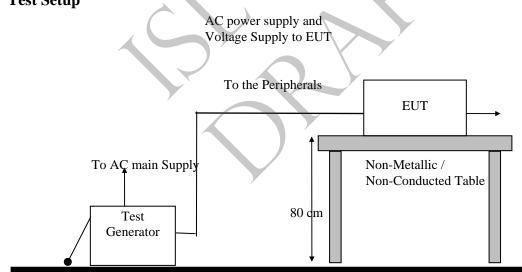


8. Surge Immunity

8.1 Test Specification

r		
Port:	AC mains	Signal and telecommunication
		port-Twisted Pair LAN Port
Basic Standard:	EN 61000-4-5/ IEC EN61000-4	4-5
	(details referred to Sec 1.2)	
Test Level:	Line to Line:	Line to Earth:
	+/- 0.5 kV, +/- 1 kV	+/- 0.5 kV, +/- 1 kV, +/- 4 kV
	Line to Earth:	
	+/- 0.5 kV, +/- 1 kV, +/- 2kV	
Rise Time:	1.2us	10us
Hold Time:	50us	700us
Repetition Rate:	30 second	60 second
Angle:	$\boxtimes 0^{\circ} \boxtimes 90^{\circ} \boxtimes 180^{\circ} \boxtimes 270^{\circ}$	NA
Criteria:	В	С
Remarks:		Where the coupling network for the 10/700 us
		waveform affects the functioning of high speed data ports, the test shall be carried out using a
		1,2/50 (8/20) us waveform and appropriate
		coupling network.
Test Procedure:	refer to ISL QA -T4-E-S10	
Temperature:	21°C	
Humidity:	65%	

8.2 Test Setup



Metal Full Soldered Ground Plane

8.3 Test Result

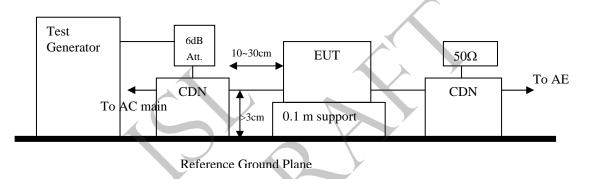


9. Immunity to Conductive Disturbance

9.1 Test specification	
Port:	AC mains; Twisted Pair LAN Port
Basic Standard:	EN 61000-4-6/ IEC EN61000-4-6
	(details referred to Sec 1.2)
Test Level:	3 V
Modulation:	AM 1KHz 80%
Frequency range:	0.15 MHz - 80MHz
Frequency Step:	1% of last Frequency
Dwell time:	38
Criteria:	А
CDN Type:	CDN M2+M3, CDN T2, CDN T4, CDN
	T8, EM Clamp
Test Procedure	refer to ISL QA -T4-E-S11
Temperature:	21°C
Humidity:	55%

9.1 Test Specification

9.2 Test Setup



9.3 Test Result

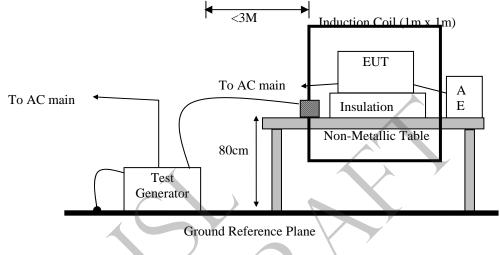


10. Power Frequency Magnetic Field immunity

10.1 Test Specification

Port:	Enclosure
Basic Standard:	EN 61000-4-8/ IEC EN61000-4-8
	(details referred to Sec 1.2)
Test Level:	1A/m
Polarization:	X, Y, Z
Criteria:	А
Test Procedure	refer to ISL QA -T4-E-S12
Temperature:	21°C
Humidity:	65%

10.2 Test Setup



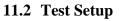
10.3 Test Result

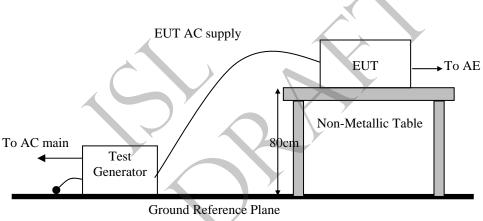


11. Voltage Dips, Short Interruption and Voltage Variation immunity

Port:	AC mains		
Basic Standard:	EN 61000-4-11/ IEC EN61000-4-11		
	(details referred to Sec 1.2)		
Test Level:	>95% in 0.5 period		
Criteria:	В		
Test Level:	30% in 25 period		
Criteria:	С		
Test Level:	>95% in 250 period		
Criteria:	С		
Phase:	0°; 180°		
Test intervals:	3 times with 10s each		
Test Procedure	refer to ISL QA -T4-E-S13		
Temperature:	21°C		
Humidity:	65%		

11.1 Test Specification





11.3 Test Result



12. Harmonics

12.1 Test Specification

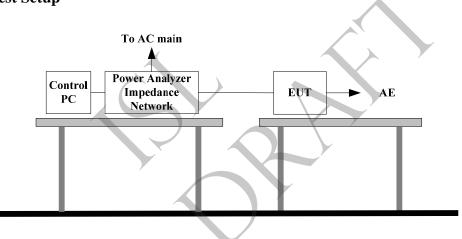
-	
Port:	AC mains
Active Input Power:	>75W
Basic Standard:	EN61000-3-2/IEC 61000-3-2
	(details referred to Sec 1.2)
Test Duration:	2.5min
Class:	D
Test Procedure	refer to ISL QA -T4-E-S14
Temperature:	22°C
Humidity:	62%

Test Procedure

The EUT is supplied in series with shunts or current transformers from a source having the same nominal voltage and frequency as the rated supply voltage and frequency of the EUT. The EUT is configured to its rated current with additional resistive load when the testing is performed.

Equipment having more than one rated voltage shall be tested at the rated voltage producing the highest harmonics as compared with the limits.

12.2 Test Setup



12.3 Test Result



20% 20% 15% Class D 10% 5.0% 0.0%

2.000A U=100% 1.000A

A0.0

1.000A U=100% 2.000A

40ms

TestData:



HAR-1000 PMC-Betuer

Full Bar : Actual Values Empty Bar : Maximum Values Blue : Current , Green : Voltage , Red : Failed

Measurement

Date : 2012/4/20 AM 11:47:3 V4.18 Urms = 229.9VFreq = 50.000Range: 2 A I rms = 0.762AIpk = 1.481A cf = 1.945 P = 142.8WS = 175.1VA = 0.815pf THDi = 27.8 %THDu = 0.10 %Class D Test - Time : 5min (100 %) Limit Reference: Pmax = 147.03WTest completed, Result: PASSED

International Standards Laboratory



<u> </u>	_	-		-		-			2
Order		Iavg							Status
1		[A]					[%]	[A]	
1	50	0.6616				0.7430			
2	100	0.0003			20 521	0.0083	20 051	0 4000	
3	150					0.1942	38.851	0.4999	
4	200	0.0000			20 020	0.0023	20. 224	0 2704	
5	250					0.0817	29.234	0.2794	
6 7	300		10 202		17 024	0.0012	10 515	0 1470	
8	350				17.934		18.515	0.1470	
8 9	400	0.0000			16 420	0.0009	16 027	0 0725	
	450 500					0.0125	10.937	0.0755	
10	500	0.0000			2 6004	0.0005	11 206	0 0515	
11 12	550 600		7.8109		2.6094	0.0039	11.386	0.0313	
12	600 650					0.0007	12 176	0 0425	
13 14	700	0.0041	9.3214		10.092	0.0037	13.170	0.0433	
14	750				22.967		24.908	0 0377	
15 16	800		0.2192		22.907	0.0094	24.900	0.0377	
10	800 850	0.0000			27.129		27.129	0 0333	
18	900	0.0000			21.129	0.0090		0.0555	
18	900 950					0.0009		0 0208	
20	1000	0.0000	19.705		1.5755	0.0005	27.802	0.0290	
20 21	1050				9.9631		11.775	0 0270	
21	1100	0.0000			7.7031	0.0007	11.775	0.0270	
22	1150					0.0063	25 792	0 0246	
23	1200				23.270		Y	0.0210	
24	1250					0.0050		0 0226	
26	1300	0.0000			7.1052		22.101	0.0220	
20	1350					0.0089	42.505	0.0210	
28	1400	0.0000	111012	0.0004		0.0010		0.0210	
29	1450	0.0000	0.0000				25.015	0.0195	
30	1500	0.0000	0.0000	0.0004		0.0009	201010	0.0170	
31	1550		10.805	0.0073			42.117	0.0183	
32	1600	0.0000		0.0004		0.0007			
33	1650		0.1683		19.214		29.178	0.0172	
34	1700	0.0000		0.0005		0.0012			
35	1750	0.0027	16.410	0.0099	61.137		62.647	0.0162	
36	1800	0.0000		0.0006		0.0015			
37	1850		26.298		27.129		40.693	0.0153	
38	1900	0.0000		0.0007		0.0017			
39	1950	0.0104	71.542	0.0134	92.514	0.0138	95.037	0.0145	
40	2000	0.0000		0.0009		0.0017			



13. Voltage Fluctuations

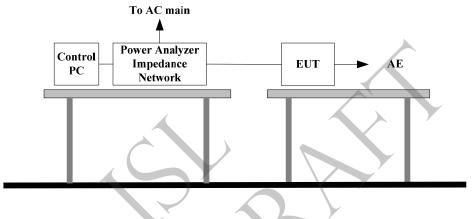
13.1 Test Specification

-			
Port:	AC mains		
Basic Standard:	EN61000-3-3/IEC61000-3-3		
	(details referred to Sec 1.2)		
Test Procedure	refer to ISL QA -T4-E-S14		
Observation period:	For Pst 10min		
	For Plt 2 hours		
Temperature:	22°C		
Humidity:	62%		

Test Procedure

The EUT is supplied in series with reference impedance from a power source with the voltage and frequency as the nominal supply voltage and frequency of the EUT.

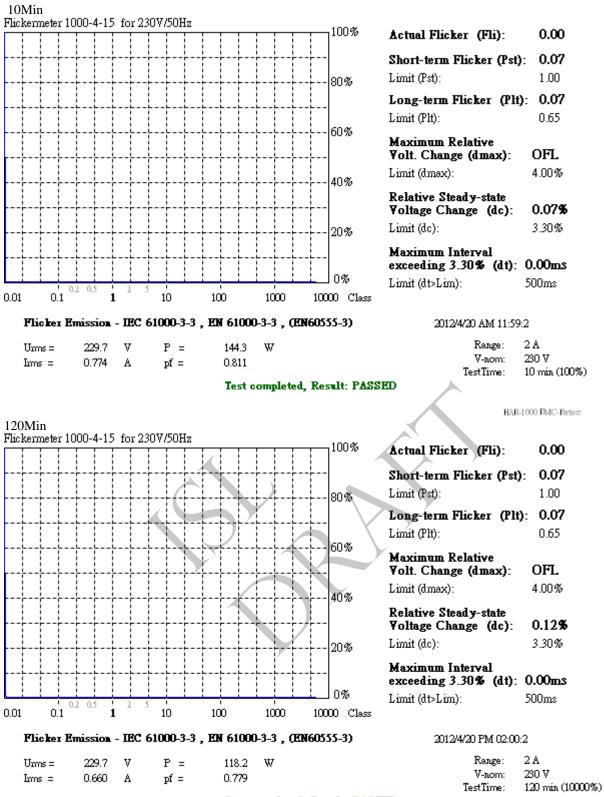
13.2 Test Setup



13.3 Test Result



TestData:



Test completed, Result: PASSED

HAR-1000 EMC-Partner



14. Appendix

14.1 Appendix A: Test Equipment

14.1.1 Test Equipment List

Location	Equipment Name	Brand	Model	S/N	Last Cal.	Next Cal.
CON01					Date	Date
Conduction	Coaxial Cable 1F-C1	EMEC	5D Cable	1F-C1	10/25/2011	10/25/2012
Conduction	LISN 02	EMCO	3825/2	1407	07/28/2011	07/28/2012
Conduction	LISN 03	R&S	ESH3-Z5 831.5518.52	828874/010	07/28/2011	07/28/2012
Conduction	ISN T2 03	FCC	FCC-TLISN-T 2-02	20618	07/28/2011	07/28/2012
Conduction	ISN T4 05	FCC	FCC-TLISN-T 4-02	20619	07/28/2011	07/28/2012
Conduction	ISN T8 03	FCC	FCC-TLINS-T 8-02	20620	07/28/2011	07/28/2012
Conduction	EMI Receiver 15	ROHDE & SCHWARZ	ESCI	101166	04/19/2012	04/19/2013

Location OATS01	Equipment Name	Brand	Model	S/N	Last Cal. Date	Next Cal. Date
Radiation	BILOG Antenna 10	Sumol Sciences	JB1	A013004-1	07/18/2011	07/18/2012
Radiation	Coaxial Cable 3F-10M	EMCI	CFD400-NL	ISL-R001	03/16/2012	03/16/2013
Radiation	EMI Receiver 13	ROHDE & SCHWARZ	ESCI	101015	02/22/2012	02/22/2013
				· · · · ·		

Location	Equipment Name	Brand	Model	S/N	Last Cal.	Next Cal.
Chamber 01					Date	Date
Rad. above 1Ghz	Horn Antenna 01	ЕМСО	3115	9504-4462	11/23/2011	11/23/2012
Rad. above 1Ghz	Horn Antenna 03	COM-Power	AH-826	100A	03/15/2011	03/15/2013
Rad. above 1Ghz	Microwave Cable-06	HUBER SUHNER	SUCFLEX 106	60404/6	07/13/2011	07/13/2012
Rad. above 1Ghz	Preamplifier 17	EMCI	EMC 01630	980009	08/03/2011	08/03/2012
Rad. above 1Ghz	Preamplifier 20	EMCI	EMC051845	980084	10/26/2011	10/26/2012
Rad. above 1Ghz	Spectrum Analyzer 23	ROHDE & SCHWARZ	FSU43	101255	10/06/2011	10/06/2012



Location	Equipment Name	Brand	Model	S/N	Last Cal. Date	Next Cal. Date
EN61K-3-2/3	DC Burn-In Load 02	D-RAM	DBS-2100	2100-910027	N/A	N/A
EN61K-3-2/3	Harmonic/Flicker Test System 03	EMC Partner	HARMONICS -1000	178	03/23/2012	03/23/2013
EN61K-4-,4,5, 8,11	TRANSIENT 2000 01	EMC Partner	TRANSIENT- 2000	950	12/01/2011	12/01/2012
EN61K-4-2	ESD GUN 04	Schaffner	NSG 438	489	03/28/2012	03/28/2013
EN61K-4-3	BILOG Antenna 06	Schaffner	CBL6112B	2754	N/A	N/A
EN61K-4-3	Amplifier 80Mz~1GHz 250W	AR	250W1000A	312494	N/A	N/A
EN61K-4-3	Amplifier 800MHz~3.0GHz 60W	AR	60S1G3	312762	N/A	N/A
EN61K-4-3	Broadband coupler 10K~220Mhz	Amplifier Research	DC2500	19810	N/A	N/A
EN61K-4-3	Broadband Coupler 80M~1GHz	Amplifier Research	DC6180	20364	N/A	N/A
EN61K-4-3	Broadband Coupler 1~4GHz	Werlatone	C5291	6516	N/A	N/A
EN61K-4-3	Coaxial Cable Chmb 04-3M-2	Belden	RG-8/U	Chmb 04-3M-2	N/A	N/A
EN61K-4-3	Signal Generator 03	Anritsu	MG3642A	6200162550	06/10/2011	06/10/2012
EN61K-4-4	Digital Oscilloscope	Tektronix	TDS 684A	B010761	N/A	N/A
EN61K-4-4	EFT Clamp	Precision	1604242	CNEFT1000-1 03	N/A	N/A
EN61K-4-5	CDN-UTP8 01	EMC Partner	CDN-UTP8	032	12/01/2011	12/01/2012
EN61K-4-5	SURGE-TESTER 01	EMC Partner	MIG0603IN3	778	12/01/2011	12/01/2012
EN61K-4-6	6dB Attenuator	Weinschel Corp	33-6-34	BC5975	N/A	N/A
EN61K-4-6	Amplifier 4-6	Amplifier Research	150A100	1-1-R-02157	N/A	N/A
EN61K-4-6	Attenuator 6dB 4-6	BIRO	100-A-FFN-06	0123	N/A	N/A
EN61K-4-6	CDN M2+M3	Frankonia	M2+M3	A3011016	07/30/2011	07/30/2012
EN61K-4-6	CDN T2 01	Frankonia	T2	A3010003	07/30/2011	07/30/2012
EN61K-4-6	CDN T4 05	FCC Inc.	FCC-801-T4-R J45		08/26/2011	08/26/2012
EN61K-4-6	CDN T8 01	FCC Inc.	FCC-801-T8-R J45	08021	08/26/2011	08/26/2012
EN61K-4-6	EM-Clamp 01	FCC	F-203I-23MM	539	N/A	N/A
EN61K-4-6	Coaxial Cable 4-6 01-1	Harbour Industries	M17/128-RG4 00	4-6 01-1	N/A	N/A
EN61K-4-6	Coaxial Cable 4-6 01-2	Harbour Industries	M17/128-RG4 00	4-6 01-2	N/A	N/A
EN61K-4-6	Coaxial Cable 4-6 01-3	Harbour Industries	M17/128-RG4 00	4-6 01-3	N/A	N/A
EN61K-4-6	KAL-AD RJ45S	BIRO			N/A	N/A
EN61K-4-6	KAL-AD T2	BIRO			N/A	N/A
EN61K-4-6	Passive Impedance Adaptor 4-6	FCC	FCC-801-150- 50-CDN	9758;9759	N/A	N/A
EN61K-4-6, CISPR 13,	Signal Generator 02	НР	8648B	3642U01040	08/18/2011	08/18/2012
Antenna EN61K-4-8	Magnetic Field Antenna	Precision	TRAIZ44B	MF1000-23	N/A	N/A
LINUIIX-4-0	magnetic Field Allellla	i iccision	I INAIZHHD	1000-23	11/17	11/ Л

 $\frac{|EN61K-4-8|}{PS: N/A => The equipment does not need calibration.}$



Test Item	Filename	Version
EN61000-3-2	HARCS.EXE	4.16
EN61000-3-3	HARCS.EXE	4.16
EN61000-4-3	Tile.Exe	2.0.P
EN61000-4-6	EN61000-4-6 Application Software	1.13.e
EN61000-4-2	N/A	2.0
EN61000-4-4	Tema.EXE	1.69
EN61000-4-5	Tema.EXE	1.69
EN61000-4-8	N/A	
EN61000-4-11	VDS-2002Rs.EXE	2.00

14.1.2 Software for Controlling Spectrum/Receiver and Calculating Test Data

Radiation/Conduction	Filename	Version	Issued Date		
Hsichih Conduction	EZ EMC	1.1.4.2	2/10/2007		
Hsichih Radiation	EZ EMC	1.1.4.2	1/24/2007		



14.2 Appendix B: Uncertainty of Measurement

The measurement uncertainty refers to CISPR 16-4-2:2003. The coverage factor k = 2 yields approximately a 95 % level of confidence.

 $<\!\!Conduction \ 01\!\!> \pm 3.262 dB$

<OATS 01 (10M)> Horizontal 30MHz~200MHz: ±4.216 dB 200MHz~1GHz: ±4.438 dB Vertical 30MHz~200MHz: ±4.342 dB 200MHz~1GHz: ±4.426 dB

<Chamber 01 (3M)> 1GHz~18GHz: ± 3.515dB 18GHz~26.5GHz: ± 3.424dB





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<immunity< th=""><th>01></th><th></th></immunity<>	01>	
Summunity	01/	

Test item	Uncertainty	
EN61000-4-2 (ESD)		
Rise time tr	$\leq 15\%$	
Peak current Ip	$\leq 6.3\%$	
current at 30 ns	$\leq 6.3\%$	
current at 60 ns	$\leq 6.3\%$	
EN61000-4-3 (RS)	± 1.776dB	
EN61000-4-4 (EFT)		
Time	$\pm 1.427\%$	
Voltage	± 1.110 %	
Current		
EN61000-4-5 (Surge)		
Time	± 0.588 %	
Voltage	\pm 1.282 %	
Current	± 1.282 %	
EN61000-4-6 (CS)	$\pm 1.892 dB$	
CDN	$\pm 1.36 dB$	
EM Clamp	± 3.19dB	
EN61000-4-8 (Magnetic)	± 1.728%	
EN61000-4-11 (Dips)		
Time	±1.159%	
Voltage	±0.100%	
Current	±1.177%	
EN61000-3-2 (Harmonics)	±1.879 %	
EN61000-3-3 (Fluctuations and Flicker)	±1.879 %	



14.3 Appendix C: Photographs of EUT Configuration Test Set Up

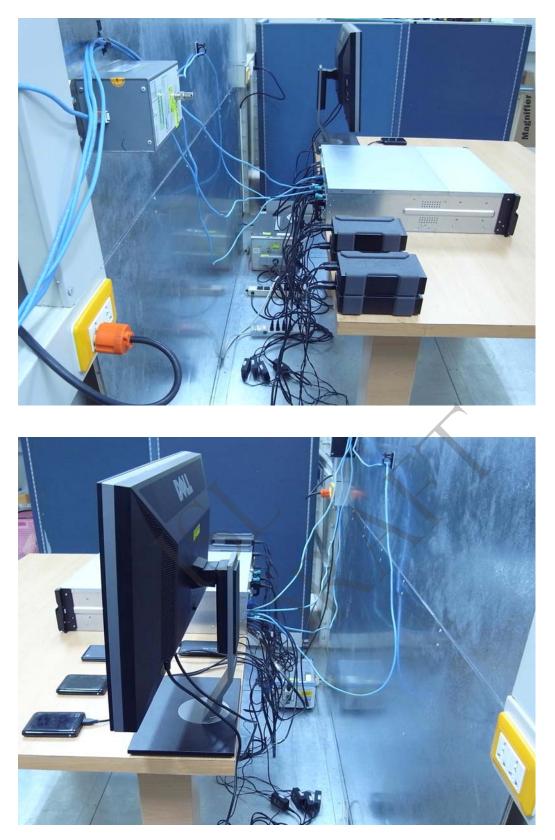
14.3.1 Photo of Main Power Port Conducted Emission and Telecommunication Port Conducted Emission Measurement

Front View











14.3.2 Photo of Radiated Emission Measurement

Front View (30MHz~1GHz)



Back View (30MHz~1GHz)







14.3.4 Photo of RF Field Strength Susceptibility Measurement





14.3.5 Photo of Electrical Fast Transient/Burst Measurement



14.3.6 Photo of Surge Measurement





14.3.7 Photo of Conductive Measurement



14.3.8 Photo of Magnetic field Measurement





14.3.9 Photo of Voltage Dips Measurement



14.3.10 Photo of Harmonics and Voltage Fluctuations



14.4 Appendix D: Photographs of EUT

Please refer to the File of ISL-12HE118P

